N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY			
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)	Q_g (Typ)
30	0.00325 @ V_{GS} = 10 V	30	36
	0.0042 @ V_{GS} = 4.5 V	27	

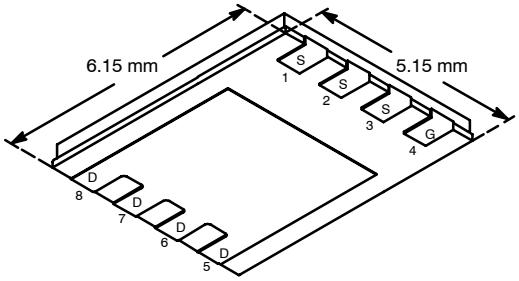
FEATURES

- Ultra-Low On-Resistance Using High Density TrenchFET® Gen II Power MOSFET Technology
- Q_g Optimized
- New Low Thermal Resistance PowerPAK® Package with Low 1.07-mm Profile
- 100% R_g Tested

APPLICATIONS

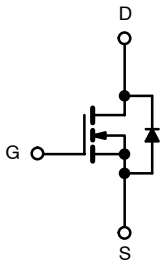
- Low-Side DC/DC Conversion
  - Notebook
  - Server
  - Workstation
- Synchronous Rectifier, POL

PowerPAK SO-8



Bottom View

Ordering Information: Si7336DP-T1



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C UNLESS OTHERWISE NOTED)					
Parameter		Symbol	10 secs	Steady State	Unit
Drain-Source Voltage		V_{DS}	30		V
Gate-Source Voltage		V_{GS}	±20		
Continuous Drain Current (T_J = 150°C)[a]	T_A = 25°C	I_D	30	18	A
	T_A = 70°C		25	15	
Pulsed Drain Current (10 μs Pulse Width)		I_{DM}	70		
Continuous Source Current (Diode Conduction)[a]		I_S	4.5	1.8	
Avalanche Current	L = 1.0 mH	I_{AS}	50		
Maximum Power Dissipation[a]	T_A = 25°C	P_D	5.4	1.9	W
	T_A = 70°C		3.4	1.2	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	−55 to 150		°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient[a]	t ≤ 10 sec	R_{thJA}	18	23	°C/W
	Steady State		50	65	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.0	1.5	

Notes
a. Surface Mounted on 1" x 1" FR4 Board.

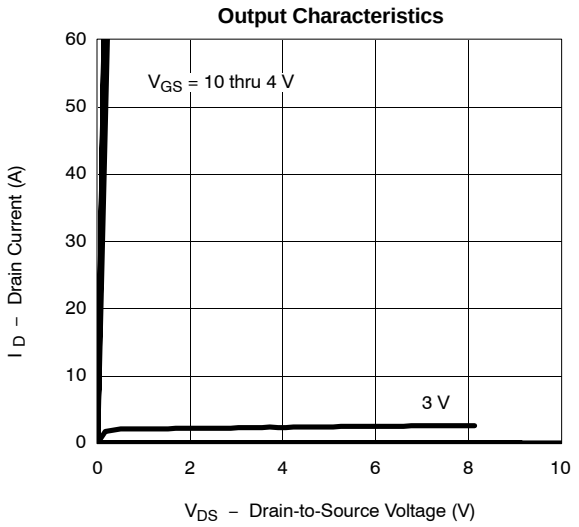
MOSFET SPECIFICATIONS (T_J = 25°C UNLESS OTHERWISE NOTED)

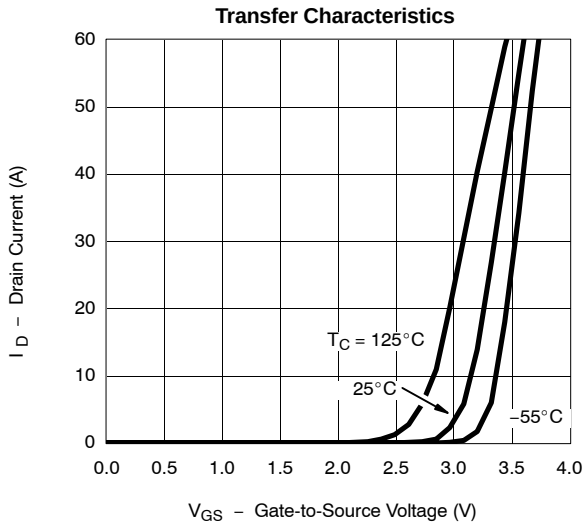
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 μA	1.0		3.0	V
Gate-Body Leakage	I_{GSS}	V_{DS} = 0 V, V_{GS} = ±20 V			±100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 30 V, V_{GS} = 0 V			1	μA
		V_{DS} = 30 V, V_{GS} = 0 V, T_J = 55°C			5	
On-State Drain Current[a]	$I_{D(on)}$	V_{DS} ≥ 5 V, V_{GS} = 10 V	30			A
Drain-Source On-State Resistance[a]	$r_{DS(on)}$	V_{GS} = 10 V, I_D = 25 A		0.0026	0.00325	Ω
		V_{GS} = 4.5 V, I_D = 19 A		0.0033	0.0042	
Forward Transconductance[a]	g_{fs}	V_{DS} = 15 V, I_D = 25 A		110		S
Diode Forward Voltage[a]	V_{SD}	I_S = 2.9 A, V_{GS} = 0 V		0.72	1.1	V
Dynamic[b]						
Input Capacitance	C_{iss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz		5600		pF
Output Capacitance	C_{oss}			860		
Reverse Transfer Capacitance	C_{rss}			415		
Total Gate Charge	Q_g	V_{DS} = 15 V, V_{GS} = 4.5 V, I_D = 20 A		36	50	nC
Gate-Source Charge	Q_{gs}			18		
Gate-Drain Charge	Q_{gd}			10		
Gate Resistance	R_g		0.8	1.3	2.0	Ω
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 15 V, R_L = 15 Ω I_D ≅ 1 A, V_{GEN} = 10 V, R_g = 6 Ω		24	35	ns
Rise Time	t_r			16	25	
Turn-Off Delay Time	$t_{d(off)}$			90	140	
Fall Time	t_f			32	50	
Source-Drain Reverse Recovery Time	t_{rr}	I_F = 2.9 A, di/dt = 100 A/μs		45	70	

Notes
a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

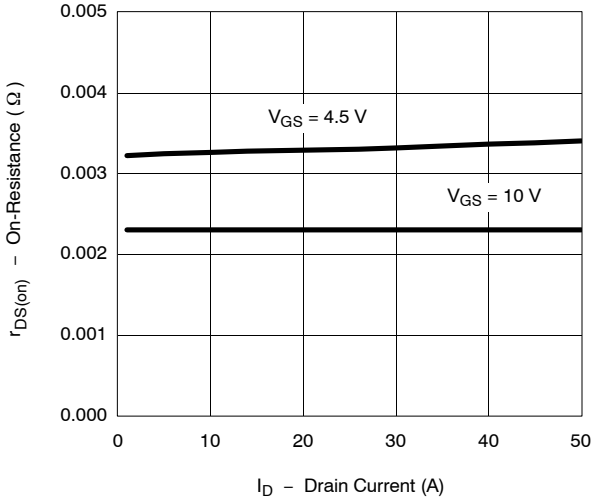
TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)



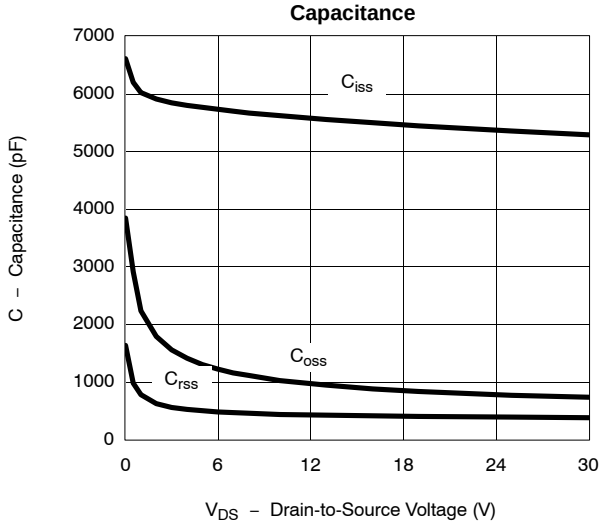


TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

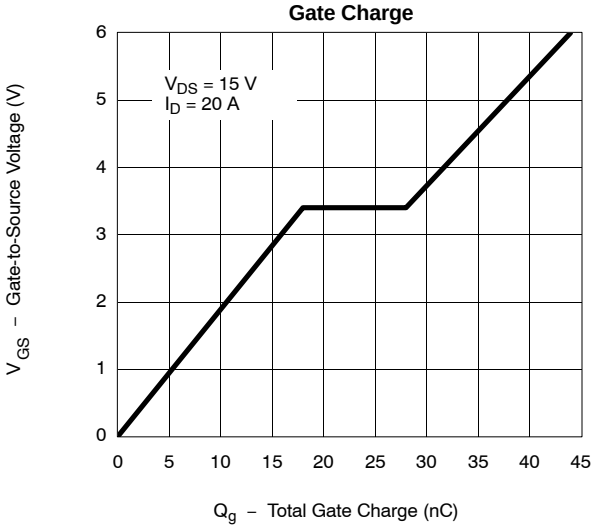
On-Resistance vs. Drain Current



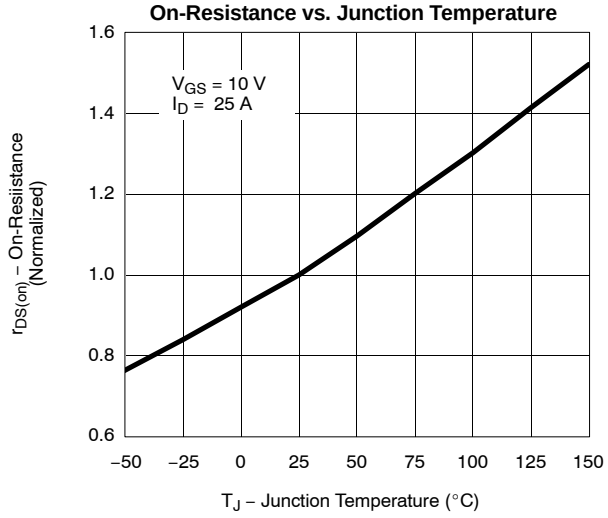
Capacitance



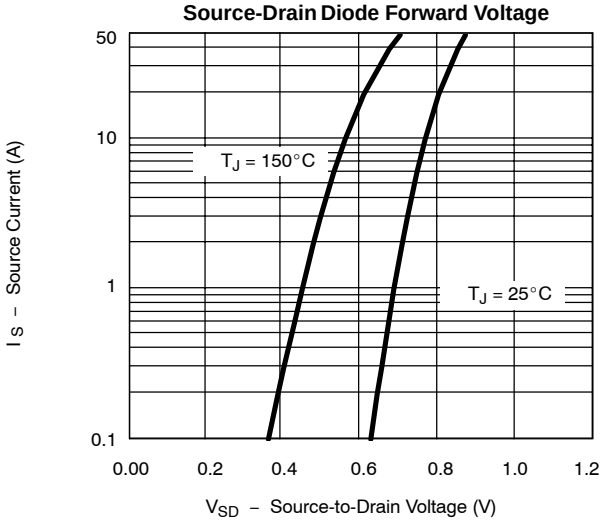
Gate Charge



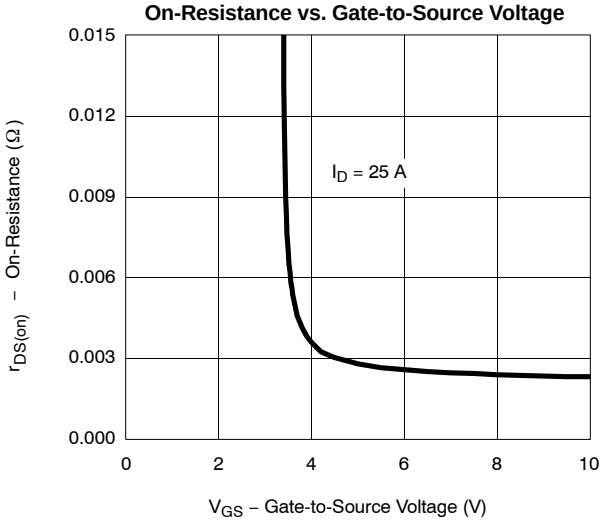
On-Resistance vs. Junction Temperature



Source-Drain Diode Forward Voltage

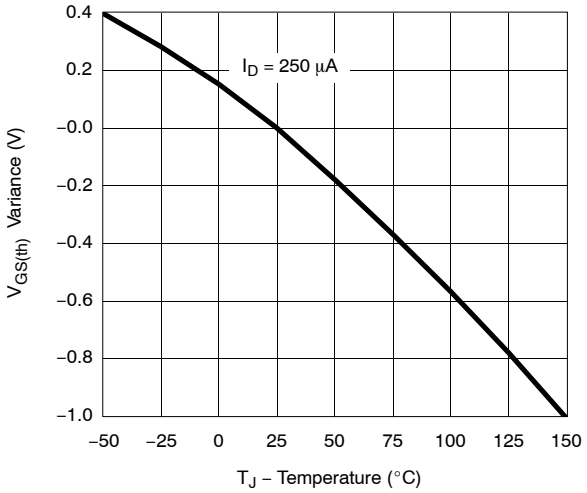


On-Resistance vs. Gate-to-Source Voltage

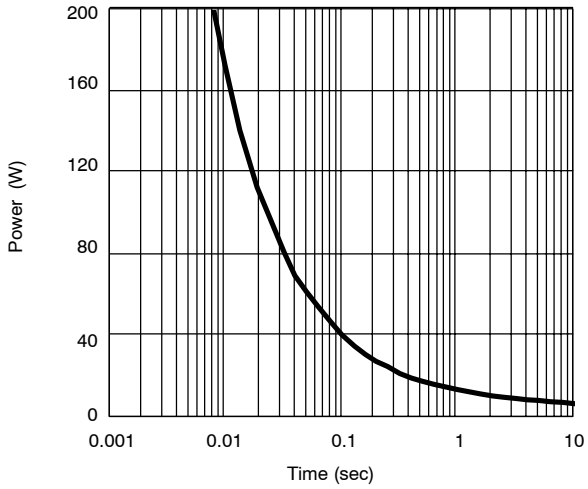


TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

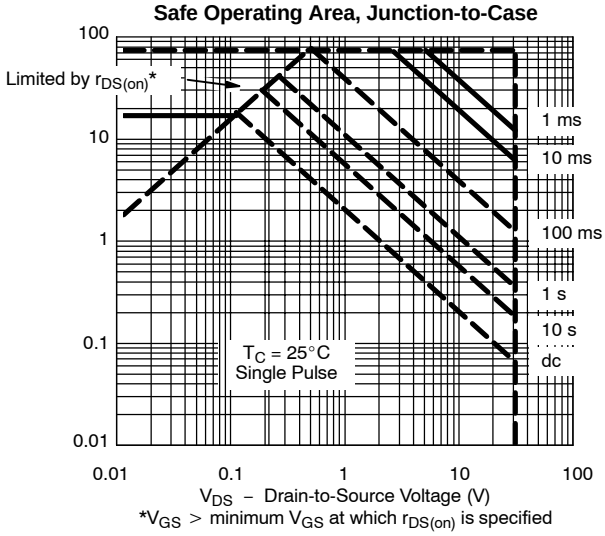
Threshold Voltage



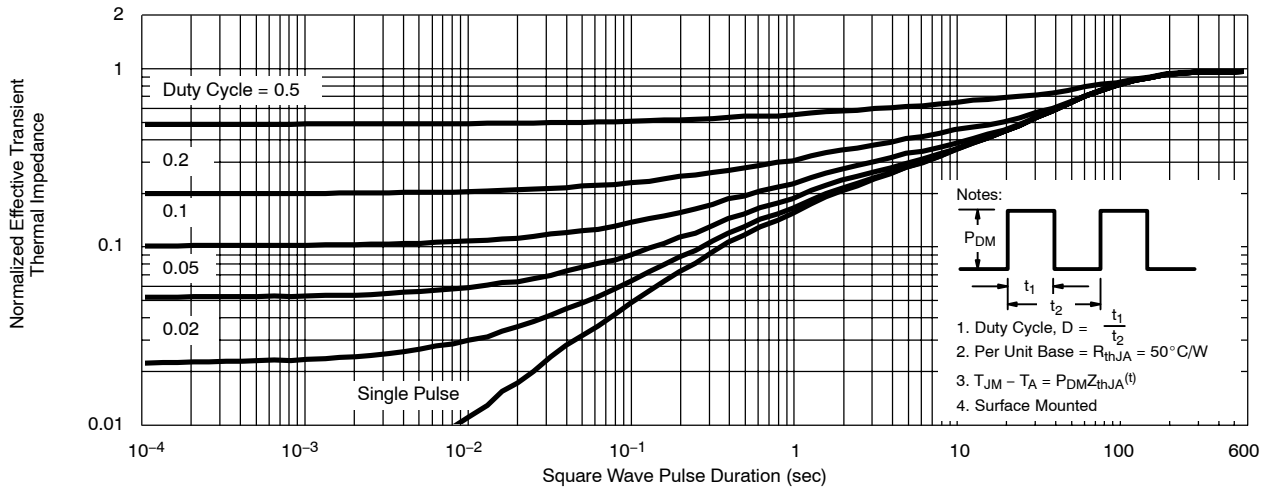
Single Pulse Power



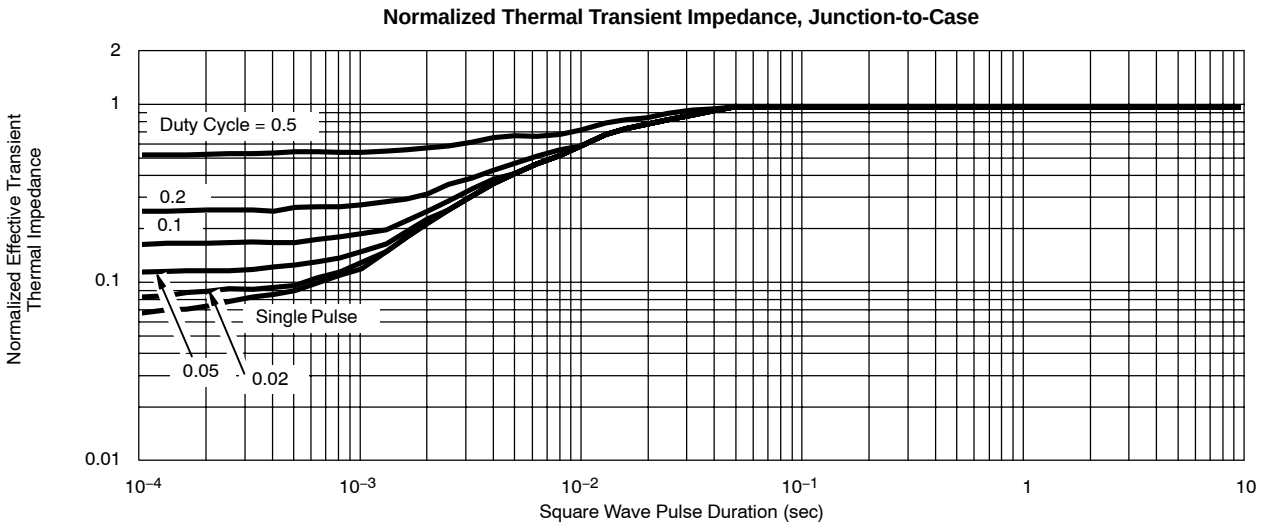
Safe Operating Area, Junction-to-Case



Normalized Thermal Transient Impedance, Junction-to-Ambient



TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)



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